Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
09/902,261	OGISHI ET AL.
Examiner	Art Unit
Chau Nguyen	2176

SEARCHED					
Class	Subclass	Date	Examiner		
715	513	8/25/2004	CN		
715	516	8/25/2004	CN		
715	517	8/25/2004	CN		
715	518	8/25/2004	CN		
715	519	8/25/2004	CN		
715	520	8/25/2004	CN		
715	521	8/25/2004	CN		
715	526	8/25/2004	CN		
715	529	8/25/2004	CN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
East Reports	8/25/2004	CN
	08/26/2004	CN
	8/30/2004	CN
Updated Search on East Reports	2/22/2005	CN
	2/23/2005	CN
Updated Search on East Reports	9/16/2005	CN
Updated Search on East Reports	3/1/2006	CN
NPL Search on IEEE Database	3/2/2006	CN